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Electrocaloric properties of ferroelectric-paraelectric superlattices controlled by the thickness of paraelectric layer in a wide temperature range

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As functions of the paraelectric layer thickness, misfit strain and temperature, the electrocaloric properties of ferroelectric-paraelectric superlattices are investigated using a time-dependent Ginzburg-Landau thermodynamic model. Ferroelectric phase transition driven by the relative thickness of the superlattice is found to dramatically impact the electrocaloric response. Near the phase transition temperature, the magnitude of the electrocaloric effect is maximized and shifted to lower temperatures by increasing the relative thickness of paraelectric layer. Theoretical calculations also imply that the electrocaloric effect of the superlattices depends not only on the relative thickness of paraelectric layer but also on misfit strain. Furthermore, control of the relative thickness of paraelectric layer and the misfit strain can change availably both the magnitude and the temperature sensitivity of the electrocaloric effect, which suggests that ferroelectric-paraelectric superlattices may be promising candidates for use in cooling devices in a wide temperature range. © 2014 Author(s). All article content, except where otherwise noted, is licensed under a Creative Commons Attribution 3.0 Unported License. [http://dx.doi.org/10.1063/1.4900858]

I. INTRODUCTION

Electrocaloric (EC) effect has generated increasing interest for application in solid-state cool-ॅं ॅं efficiency, efficient heat transfer, large breakdown fields and so on.

EC cooling, based on electric-field-driven temperature changes near phase transitions of ferro-ॅं, geneein ॅं, Finger, Fing effect by experiments and theory.^{3,5} However, FTFs cannot pump significant heat and the heat is often thermally absorbed by substrates. Ferroelectric multilayer structures (FMSs), consisting of many



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FTFs, have been proposed as the promising candidates forward towards practical EC cooler.^{10–12} Giant EC effect can be achieved in FMSs with efficient heat transfer due to the large surface-to-volume ratio of the constituent FTFs.¹³ FMSs have been shown to overcome the disadvantages identified in bulk and films while preserving all of the corresponding advantages. Therefore FMS represents the optimal geometry for EC cooling applications.

Theoretically, the thermodynamic model based on Landau theory has been developed to predict the EC effect of FTFs, nanoparticle and multilayer. In this paper, we employ time-dependent Ginzburg-Landau (TDGL) theory to investigate the EC effect of FPS. The adiabatic temperatures are calculated as functions of the relative thickness of paraelectric layer, applied electric field, misfit strain and temperature. The simulations show that the magnitude of the EC effect in FPS and its dependence on temperature can be controlled by the relative thickness of paraelectric layer and misfit strain. In other words, we could obtain the desired EC effect of FPS through carefully choosing the thickness of PT and ST layer and substrate materials.

II. SIMULATION METHODOLOGY

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$$\frac{\partial \mathbf{P}^m(x_i,t)}{\partial t} = -L \frac{\delta F}{\delta \mathbf{P}^m(x_i,t)},\tag{1}$$





FIG. 1. Schematic structures of (a) an epitaxial A/B superlattice on a substrate and (b) the simulation cell.

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$$F^{m} = F_{\text{Bulk}}^{m} + F_{\text{Ela}}^{m} + F_{\text{G}}^{m} + F_{\text{E}}^{m} + F_{\text{I}}^{m}$$

= $\iiint_{V} \left(f_{\text{Bulk}}^{m} + f_{\text{Ela}}^{m} + f_{\text{G}}^{m} + f_{\text{E}}^{m} \right) dV + \iint_{S} f_{\text{I}}^{m} dS$ (2)

$$\begin{aligned} f_{\text{Bulk}}^{m} + f_{\text{Ela}}^{m} &= \alpha_{1}^{m*} \left[\left(P_{1}^{m} \right)^{2} + \left(P_{2}^{m} \right)^{2} \right] + \alpha_{3}^{m*} \left(P_{3}^{m} \right)^{2} + \alpha_{11}^{m*} \left[\left(P_{1}^{m} \right)^{4} + \left(P_{2}^{m} \right)^{4} \right] \\ &+ \alpha_{33}^{m*} \left(P_{3}^{m} \right)^{4} + \alpha_{12}^{m*} \left(P_{1}^{m} \right)^{2} \left(P_{2}^{m} \right)^{2} + \alpha_{13m}^{m} \left[\left(P_{1}^{m} \right)^{2} + \left(P_{2}^{m} \right)^{2} \right] \left(P_{3}^{m} \right)^{2} \\ &+ \alpha_{111}^{m} \left[\left(P_{1}^{m} \right)^{6} + \left(P_{2}^{m} \right)^{6} + \left(P_{3}^{m} \right)^{6} \right] + \alpha_{112}^{m} \left\{ \left(P_{1}^{m} \right)^{4} \left[\left(P_{2}^{m} \right)^{2} + \left(P_{3}^{m} \right)^{2} \right] \right\} \\ &+ \left(P_{2}^{m} \right)^{4} \left[\left(P_{1}^{m} \right)^{2} + \left(P_{3}^{m} \right)^{2} \right] + \left(P_{3}^{m} \right)^{4} \left[\left(P_{1}^{m} \right)^{2} + \left(P_{2}^{m} \right)^{2} \right] \right\} \\ &+ \alpha_{123}^{m} \left(P_{1}^{m} \right)^{2} \left(P_{2}^{m} \right)^{2} \left(P_{3}^{m} \right)^{2} + \frac{\left(u_{\text{mis}}^{m} \right)^{2}}{s_{11}^{m} + s_{12}^{m}} \end{aligned}$$
(3)

where the renormalized coefficients is expressed as

$$\begin{aligned} \alpha_{1}^{m*} &= \alpha_{1}^{m} - u_{\text{mis}}^{m} \frac{Q_{11}^{m} + Q_{12}^{m}}{s_{11}^{m} + s_{12}^{m}}, \\ \alpha_{3}^{m*} &= \alpha_{1}^{m} - u_{\text{mis}}^{m} \frac{2Q_{12}^{m}}{s_{11}^{m} + s_{12}^{m}}, \\ \alpha_{11}^{m*} &= \alpha_{11}^{m} + \frac{\left\{ \left[(Q_{11}^{m})^{2} + (Q_{12}^{m})^{2} \right] s_{11}^{m} - 2Q_{11}^{m}Q_{12}^{m}s_{12}^{m} \right\} }{2 \left[(s_{11}^{m})^{2} - (s_{12}^{m})^{2} \right]}, \\ \alpha_{12}^{m*} &= \alpha_{12}^{m} - \frac{\left\{ \left[(Q_{11}^{m})^{2} + (Q_{12}^{m})^{2} \right] s_{12}^{m} - 2Q_{11}^{m}Q_{12}^{m}s_{11}^{m} \right\} }{\left[(s_{11}^{m})^{2} - (s_{12}^{m})^{2} \right]} + \frac{(Q_{44}^{m})^{2}}{2s_{44}^{m}}, \end{aligned}$$
(4)
$$\alpha_{13}^{m*} &= \alpha_{12}^{m} + \frac{Q_{12}^{m}(Q_{11}^{m} + Q_{12}^{m})}{s_{11}^{m} + s_{12}^{m}}, \\ \alpha_{33}^{m*} &= \alpha_{11}^{m} + \frac{(Q_{12}^{m})^{2}}{s_{11}^{m} + s_{12}^{m}}, \end{aligned}$$

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$$f_{\rm G}^{m} = \frac{1}{2} G_{11}^{m} \left[\left(P_{1,1}^{m} \right)^{2} + \left(P_{2,2}^{m} \right)^{2} + \left(P_{3,3}^{m} \right)^{2} \right] + G_{12}^{m} \left(P_{1,1}^{m} P_{2,2}^{m} + P_{2,2}^{m} P_{3,3}^{m} + P_{1,1}^{m} P_{3,3}^{m} \right) \\ + \frac{1}{2} G_{44}^{m} \left[\left(P_{1,2}^{m} + P_{2,1}^{m} \right)^{2} + \left(P_{2,3}^{m} + P_{3,2}^{m} \right)^{2} + \left(P_{1,3}^{m} + P_{3,1}^{m} \right)^{2} \right] \\ + \frac{1}{2} G_{44}^{m'} \left[\left(P_{1,2}^{m} - P_{2,1}^{m} \right)^{2} + \left(P_{2,3}^{m} - P_{3,2}^{m} \right)^{2} + \left(P_{1,3}^{m} - P_{3,1}^{m} \right)^{2} \right]$$
(5)

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According to the previous works^{18–20,31,32} the electric energy density of a given polarization distribution is expressed as

$$f_{\rm E}^m = -E_i^m P_i^m - \frac{1}{2} \varepsilon_{\rm b} E_i^m E_i^m \tag{6}$$

Taking interfacial coupling between layers A and B into account, the boundary conditions for the polarizations at the interfaces x=0 are

$$\frac{dP_i^A}{dx_3}\Big|_{x_3=0^-} = -\frac{P_i^A(0)}{\delta_i^A} + \frac{\xi_i P_i^B(0)}{D_{ij}^A} \\
\frac{dP_i^B}{dx_3}\Big|_{x_3=0^+} = \frac{P_i^B(0)}{\delta_i^B} - \frac{\xi_i P_i^A(0)}{D_{ij}^B}$$
(7)

$$\frac{dP_{i}^{A}}{dx_{3}}\bigg|_{x_{3}=-h_{A}} = \frac{P_{i}^{A}(-h_{A})}{\delta_{i}^{A}} - \frac{\xi_{i}P_{i}^{B}(h_{B})}{D_{ij}^{A}}$$

$$\frac{dP_{i}^{B}}{dx_{3}}\bigg|_{x_{3}=h_{B}} = -\frac{P_{i}^{B}(h_{B})}{\delta_{i}^{B}} + \frac{\xi_{i}P_{i}^{A}(-h_{A})}{D_{ij}^{B}}$$
(8)

After further derivations obtained from Maxwell relations, as a uniform electric field is applied to a dielectric solid, the EC coefficient is described as^{4,5,33}

$$p_i = \left(\frac{\partial S}{\partial E_i}\right)_T = \left(\frac{\partial D_i}{\partial T}\right)_E \tag{9}$$

The adiabatic temperature change ΔT in the dielectric material due to a change in external electric field is written by

$$\Delta T = -\frac{T}{C_E} \int_{E_a}^{E_b} \left(\frac{\partial D_i}{\partial T}\right)_E dE \tag{10}$$

where C_E is the heat capacity per unit volume at constant electric field, E_a and E_b are the starting and final applied fields, respectively.

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in the form,

$$D_i = \varepsilon_b E_i + P_i = \varepsilon_b E'_i + \varepsilon_b E^d_i + P_i \tag{11}$$

By considering that E'_i is independent on temperature and E^d_i is a function of temperature, we redefine the EC coefficient of the ferroelectric nanostructures caused by the external electric field as,

$$p_{i} = \left[\frac{\partial(\varepsilon_{b}E_{i}^{d} + P_{i})}{\partial T}\right]_{E'} = \left(\frac{\partial P_{i}^{0}}{\partial T}\right)_{E'}$$
(12)

$$\Delta T = -\frac{T}{C_E} \int_{E_a}^{E_b} \left(\frac{\partial P_i^0}{\partial T} \right)_{E'} dE'$$
(13)

III. RESULTS AND DISCUSSION

A. The electrocaloric effect of FPS

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B. Influence of the ST layer relative thickness on EC effect

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C. Mechanical regulation of EC effect in FPS

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IV. CONCLUSION

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ACKNOWLEDGMENTS

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